



COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)}	I _D T _A = 25°C
Q1	20V	$35m\Omega$ @ $V_{GS} = 4.5V$	4.5A
3	Q1 20V	$56m\Omega$ @ $V_{GS} = 1.8V$	3.5A
03	201/	$74mΩ @ V_{GS} = -4.5V$	3.1A
Q2	-20V	168mΩ @ $V_{GS} = -1.8V$	2.0A

Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- · Fast Switching Speed
- Low Input/Output Leakage
- Fast Switching Speed
- Lead Free By Design/RoHS Compliant (Note 1)
- "Green" Device (Note 2)
- Qualified to AEC-Q101 standards for High Reliability

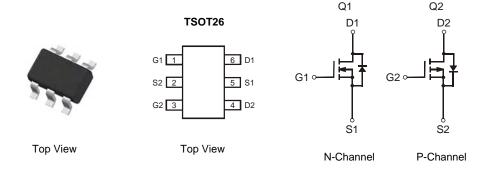
Description and Applications

This MOSFET has been designed to minimize the on-state resistance $(R_{DS(on)})$ and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Motor control
- Power Management Functions
- DC-DC Converters
- Backlighting

Mechanical Data

- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish NiPdAu over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.027 grams (approximate)



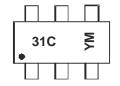
Ordering Information (Note 3)

Part Number	Case	Packaging
DMC2038LVT-7	TSOT26	3000/Tape & Reel

Notes:

- 1. No purposefully added lead.
- 2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com.

Marking Information



31C = Product Type Marking Code YM = Date Code Marking Y = Year (ex: X = 2010) M = Month (ex: 9 = September)

Date Code Key

Year	2010	0	2011		2012	20	13	2014		2015		2016
Code	X		Y		Z	/	4	В		С		D
Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D

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Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 4)	P _D	1.13	W
Thermal Resistance, Junction to Ambient (Note 4)	$R_{ heta JA}$	114	°C/W
Thermal Resistance, Junction to Case (Note 4)	$R_{ heta Jc}$	38.5	°C/W
Total Power Dissipation (Note 5)	P _D	0.77	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{ heta JA}$	168	°C/W
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

Maximum Ratings N-CHANNEL − Q1 @T_A = 25°C unless otherwise specified

Characteristic		Symbol	Value	Units	
Drain-Source Voltage			V_{DSS}	20	V
Gate-Source Voltage			V_{GSS}	±12	V
Continuous Drain Current (Note 4) V _{GS} = 4.5V	Steady State	T _A = 25°C T _A = 70°C	I _D	4.5 3.6	А
Continuous Drain Current (Note 4) V _{GS} = 1.8V	Steady State	T _A = 25°C T _A = 70°C	I _D	3.5 2.8	А
Continuous Drain Current (Note 5) V _{GS} = 4.5V	Steady State	T _A = 25°C T _A = 70°C	I _D	3.7 3.0	А
Continuous Drain Current (Note 5) V _{GS} = 1.8V	Steady State	T _A = 25°C T _A = 70°C	I _D	2.9 2.3	А
Pulsed Drain Current (Note 6)		I _{DM}	17	А	

Maximum Ratings P-CHANNEL – Q2@T_A = 25°C unless otherwise specified

Characteristic		Symbol	Value	Units	
Drain-Source Voltage			V _{DSS}	-20	V
Gate-Source Voltage			V_{GSS}	±12	V
Continuous Drain Current (Note 4) V _{GS} = 4.5V	Steady State	$T_A = 25$ °C $T_A = 70$ °C	I _D	3.1 2.5	А
Continuous Drain Current (Note 4) V _{GS} = 1.8V	Steady State	$T_A = 25$ °C $T_A = 70$ °C	I _D	2.0 1.6	А
Continuous Drain Current (Note 5) V _{GS} = 4.5V	Steady State	$T_A = 25$ °C $T_A = 70$ °C	I _D	2.6 2.1	А
Continuous Drain Current (Note 5) V _{GS} = 1.8V	Steady State	$T_A = 25$ °C $T_A = 70$ °C	I _D	1.7 1.3	А
Pulsed Drain Current (Note 6)			I _{DM}	-12	Α

^{4.} Device mounted on FR-4 substrate PC board, 2oz copper, on 1inch square copper plate.
5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout
6. Device mounted on minimum recommended pad layout test board, 10µs pulse duty cycle = 1%.

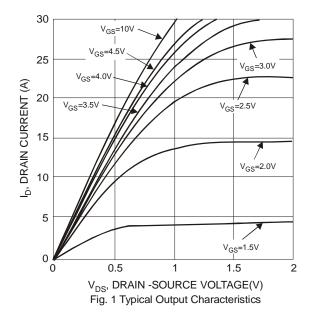


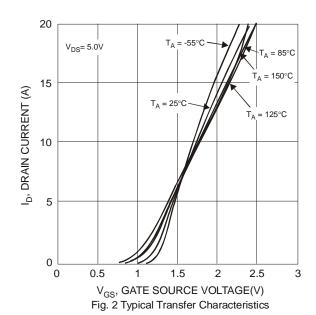
Electrical Characteristics N-CHANNEL - Q1@TA = 25°C unless otherwise specified

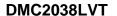
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage		BV _{DSS}	20	-	-	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	$@T_c = 25^{\circ}C$	I_{DSS}	-	-	1.0	μΑ	$V_{DS} = 16V, V_{GS} = 0V$
Gate-Source Leakage		I_{GSS}	1	-	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage		$V_{GS(th)}$	0.4	-	1.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
			-	27	35		$V_{GS} = 4.5V, I_D = 4.0A$
Static Drain-Source On-Resistance		R _{DS (ON)}	-	33	43	$m\Omega$	$V_{GS} = 2.5V, I_D = 2.5A$
			-	43	56		$V_{GS} = 1.8V, I_D = 1.5A$
Forward Transfer Admittance		Y _{fs}	-	9	-	S	$V_{DS} = 5V, I_D = 3.4A$
Diode Forward Voltage		V_{SD}	0.4	-	1.1	V	$V_{GS} = 0V, I_{S} = 1A$
Maximun Body-Diode Continuous Current		Is	-	-	4.5	Α	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance		C _{iss}	-	400	530	pF	101/1/
Output Capacitance		C_{oss}	-	70	90	pF	$V_{DS} = 10V, V_{GS} = 0V,$ -f = 1.0MHz
Reverse Transfer Capacitance		C_{rss}	-	65	100	pF	1 = 1.000112
Gate Resistance		R_g	-	1.9	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = 4.5V)		Qg	-	5.7	-	nC	
Total Gate Charge (V _{GS} = 10V)		Qg	-	12	17	nC	$V_{GS} = 10V, V_{DS} = 15V,$
Gate-Source Charge		Q _{gs}	-	0.7	-	nC	I _D = 5.8A
Gate-Drain Charge		Q _{qd}	-	1.4	-	nC	
Turn-On Delay Time		t _{D(on)}	-	5	10	ns	
Turn-On Rise Time		t _r	-	8	16	ns	$V_{DS} = 10V, V_{GS} = 4.5V,$
Turn-Off Delay Time		t _{D(off)}	-	25	40	ns	$R_G = 6\Omega$, $I_{DS} = 1A$,
Turn-Off Fall Time		t _f	-	8	16	ns	

Notes:

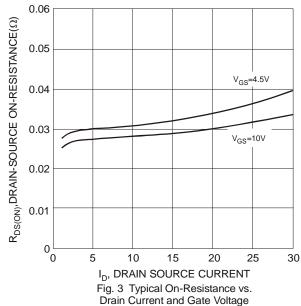
- 7. Short duration pulse test used to minimize self-heating effect.
- 8. Guaranteed by design. Not subject to product testing.

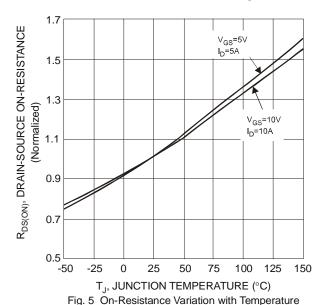












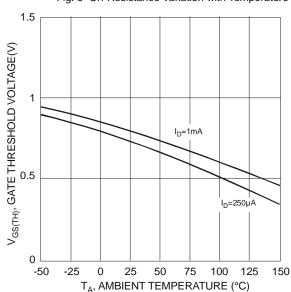
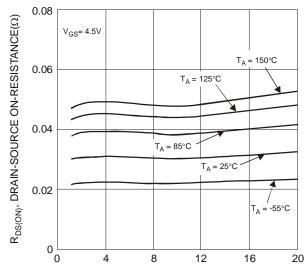


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



I_D, DRAIN SOURCE CURRENT (A) Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

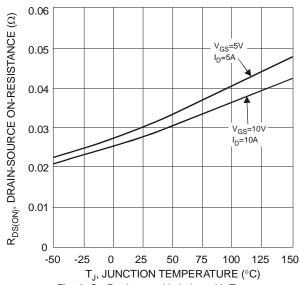
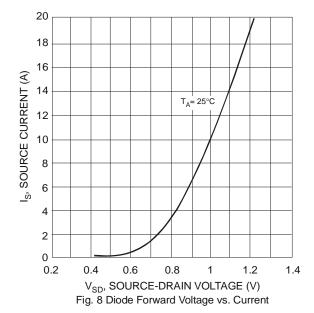
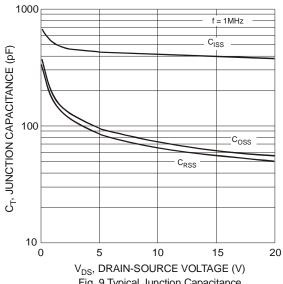
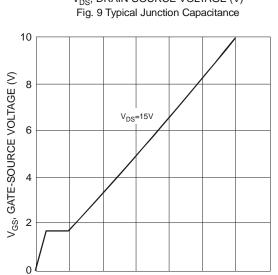


Fig. 6 On-Resistance Variation with Temperature









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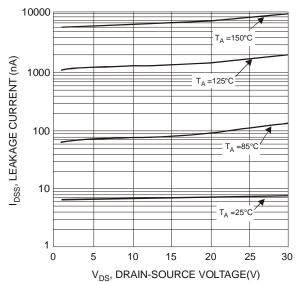
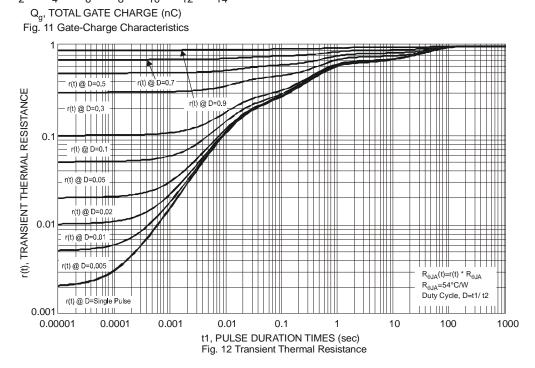


Fig. 10 Typical Drain-Source Leakage Current vs. Voltage



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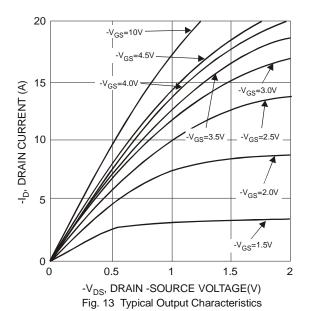


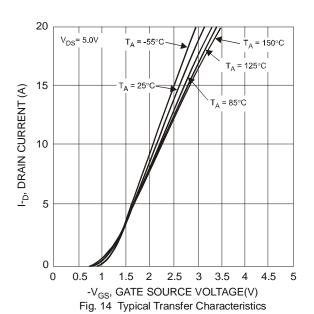
Electrical Characteristics P-CHANNEL - Q2@TA = 25°C unless otherwise specified

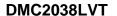
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)					•		
Drain-Source Breakdown Voltage	BV _{DSS}	-20	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current @Tc = 2	5°C I _{DSS}	-	-	-1.0	μA	$V_{DS} = -16V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	-	-	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V _{GS(th)}	-0.4	-	-1.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
		-	57	74		$V_{GS} = -4.5V, I_D = -3.0A$	
Static Drain-Source On-Resistance	R _{DS} (ON)	-	76	110	mΩ	$V_{GS} = -2.5V, I_D = -1.5A$	
		-	102	168		$V_{GS} = -1.8V, I_D = -1.0A$	
Forward Transfer Admittance	Y _{fs}	-	10	-	S	$V_{DS} = -5V, I_{D} = -3.0A$	
Diode Forward Voltage (Note 6)	V_{SD}	-	-0.8	-1.0	V	$V_{GS} = 0V, I_{S} = -0.6A$	
Maximun Body-Diode Continuous Current	Is	-	-	-3.2	Α		
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	-	530	705	pF	101/11/	
Output Capacitance	Coss	-	70	95	pF	$V_{DS} = -10V, V_{GS} = 0V,$ -f = 1.0MHz	
Reverse Transfer Capacitance	C _{rss}	-	60	90	pF	T = 1.0WHZ	
Gate Resistance	Rq	-	72	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = -4.5V)	Qg	-	7	10	nC		
Total Gate Charge (V _{GS} = -10V)	Qg	-	14	-	nC	$V_{GS} = -10V, V_{DS} = -15V,$	
Gate-Source Charge	Q _{gs}	-	0.95	-	nC	I _D = -6A	
Gate-Drain Charge	Q _{qd}	-	1.2	-	nC	1	
Turn-On Delay Time	t _{D(on)}	-	11	20	nS		
Turn-On Rise Time	t _r	-	12	22	nS	$V_{DS} = -10V, V_{GS} = -4.5V,$	
Turn-Off Delay Time	t _{D(off)}	-	21	34	nS	$R_G = 6\Omega$, $I_S = -1A$,	
Turn-Off Fall Time	t _f	-	13	23	nS		

Notes:

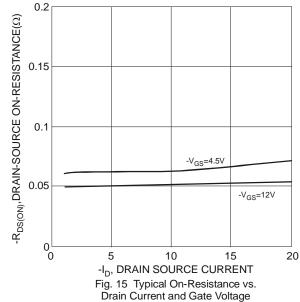
- 7. Short duration pulse test used to minimize self-heating effec 8. Guaranteed by design. Not subject to product testing.

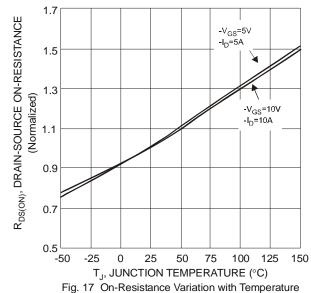












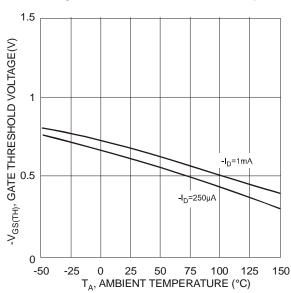
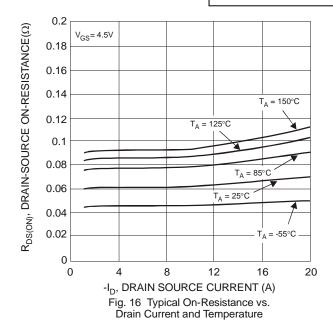
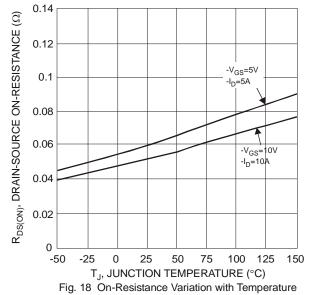


Fig. 19 Gate Threshold Variation vs. Ambient Temperature



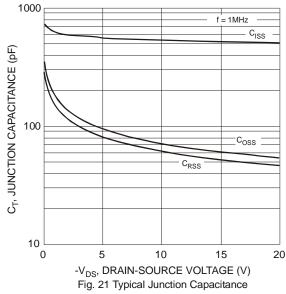


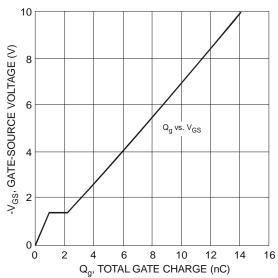
20 18 -I_S, SOURCE CURRENT (A) T_A= 25°C 14 12 10 8 6 2 0 0.2 0.4 8.0 1.2 0.6 1 1.4 1.6 -V_{SD}, SOURCE-DRAIN VOLTAGE (V)

Fig. 20 Diode Forward Voltage vs. Current









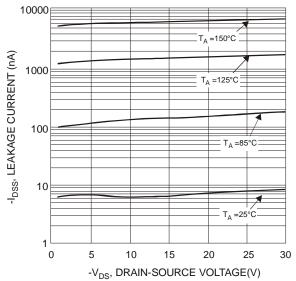
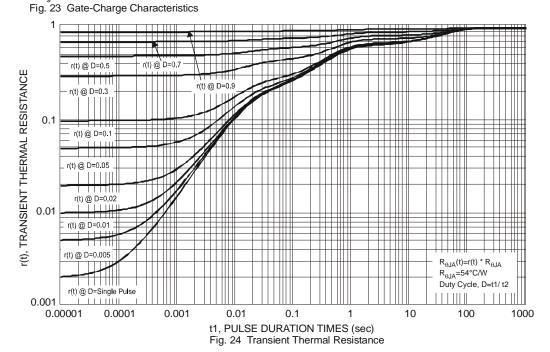
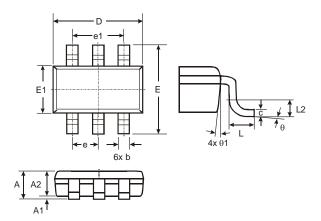


Fig. 22 Typical Drain-Source Leakage Current vs. Voltage



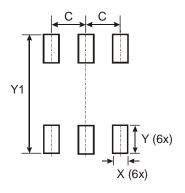


Package Outline Dimensions



	TSOT26							
Dim	Min	Max	Тур					
Α	1	1.00	1					
A 1	0.01	0.10	-					
A2	0.84	0.90	1					
D	-	-	2.90					
Е	_	_	2.80					
E1	-	-	1.60					
b	0.30	0.45	1					
С	0.12	0.20	-					
е	_	_	0.95					
e1	_	_	1.90					
L	0.30	0.50						
L2	-	-	0.25					
θ	0°	8°	4°					
θ1	4°	12°	_					
All D	imens	ions ir	n mm					

Suggested Pad Layout



Dimensions	Value (in mm)
С	0.950
Х	0.700
Y	1.000
Y1	3.199



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 - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
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